

SANYO Semiconductors DATA SHEET

P-Channel Silicon MOSFET

FTD1028 — General-Purpose Switching Device Applications

Features

- · Low ON-resistance.
- · 2.5V drive.
- Mounting height 1.1mm.
- · Composite type, facilitating high-density mounting.

Specifications

Absolute Maximum Ratings at Ta=25°C

Parameter	Symbol	Conditions	Ratings	Unit
Drain-to-Source Voltage	V _{DSS}		-20	V
Gate-to-Source Voltage	VGSS		±10	V
Drain Current (DC)	ID		-3	Α
Drain Current (Pulse)	IDP	PW≤10μs, duty cycle≤1%	-15	Α
Allowable Power Dissipation	PD	Mounted on a ceramic board (1000mm ² X0.8mm) 1unit	0.8	W
Total Power Dissipation	PT	Mounted on a ceramic board (1000mm ² X0.8mm)	1.0	W
Channel Temperature	Tch		150	°C
Storage Temperature	Tstg		-55 to +150	°C

Electrical Characteristics at Ta=25°C

Parameter	Symbol	Conditions	Ratings			Linit
			min	typ	max	Unit
Drain-to-Source Breakdown Voltage	V(BR)DSS	ID=-1mA, VGS=0V	-20			V
Zero-Gate Voltage Drain Current	IDSS	V _{DS} =-20V, V _{GS} =0V			-1	μΑ
Gate-to-Source Leakage Current	IGSS	V _{GS} =±8V, V _{DS} =0V			±10	μΑ
Cutoff Voltage	VGS(off)	V _{DS} =-10V, I _D =-1mA	-0.4		-1.4	V
Forward Transfer Admittance	yfs	V _{DS} =-10V, I _D =-2A	3.8	6.3		S
Static Drain-to-Source On-State Resistance	R _{DS} (on)1	I _D =-2A, V _G S=-4V		55	77	mΩ
	RDS(on)2	ID=-1A, VGS=-2.5V		81	113	mΩ
Input Capacitance	Ciss	V _{DS} =-10V, f=1MHz		900		pF
Output Capacitance	Coss	V _{DS} =-10V, f=1MHz		125		pF
Reverse Transfer Capacitance	Crss	VDS=-10V, f=1MHz		115		pF
Turn-ON Delay Time	t _d (on)	See specified Test Circuit.		16		ns
Rise Time	t _r	See specified Test Circuit.		54		ns
Turn-OFF Delay Time	t _d (off)	See specified Test Circuit.		107		ns
Fall Time	tf	See specified Test Circuit.		82		ns

Marking: D1028 Continued on next page.

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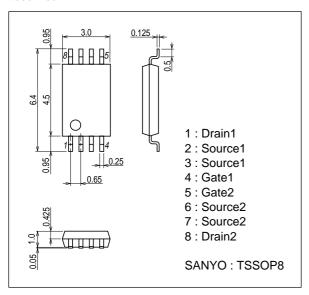
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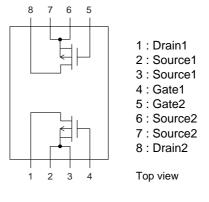
Parameter	Symbol	Conditions	Ratings			Unit
			min	typ	max	Offic
Total Gate Charge	Qg	V _{DS} =-10V, V _{GS} =-4V, I _D =-3A		9.3		nC
Gate-to-Source Charge	Qgs	V _{DS} =-10V, V _{GS} =-4V, I _D =-3A		2.5		nC
Gate-to-Drain "Miller" Charge	Qgd	V _{DS} =-10V, V _{GS} =-4V, I _D =-3A		1.9		nC
Diode Forward Voltage	VSD	IS=-3A, VGS=0V		-0.84	-1.2	V

Package Dimensions

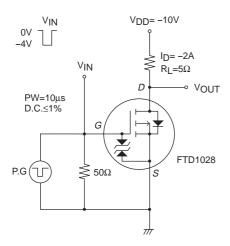
unit : mm (typ) 7006A-002

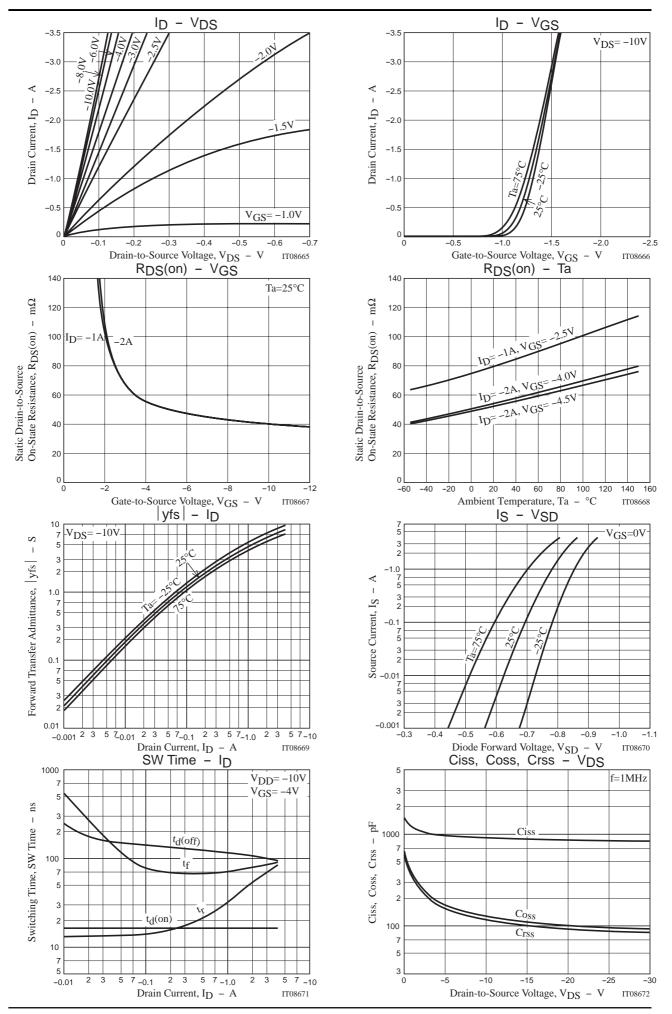


Electrical Connection

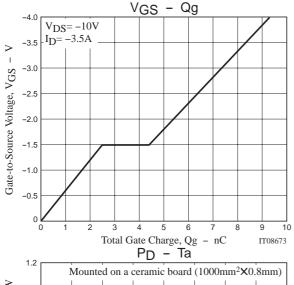


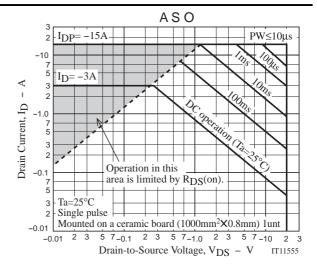
Switching Time Test Circuit

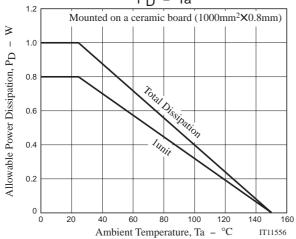




FTD1028







Note on usage: Since the FTD1028 is a MOSFET product, please avoid using this device in the vicinity of highly charged objects.

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